Form PTO-1449

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

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ATTY. DOCKET NO.

SERIAL NO. 10/050,347

APPLICANT Gurtej S. Sandhu

LIST OF ART CITED BY APPLICANT **GROUP** FILING DATE (Use several sheets if necessary) January 15, 2002 2813 **U.S. PATENT DOCUMENTS** Date Class Subclass Filing Date Document Name Examiner If Appropriate Initial Number AA 3,627,598 12/71 McDonald et al. AB 4,254,161 03/81 Kemlage Kubacki AC 04/81 4,262,631 AD 4,435,447 03/84 Ito et al. 4,882,649 11/89 Chen et al. AF 4,891,684 01/90 Nishioka et al. AG 12/90 Ito et al. 4,980,307 Ellul et al. ΑН 4,996,081 02/91 09/91 5,051,794 Mori 08/92 5,142,438 Reinberg et al. FOREIGN PATENT DOCUMENTS Class Subclass Translation Document Date Country Number Yes No EP 0886308 A2 12/98 **EPO** 237243 a 04/01 Japan OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) Wolf, Stanley, Silicon Processing for the VLSI Era (1995), V.3, 648-9 AN ΑO Laughery et al., Effect of H₂ Content on Reliability of Ultrathin In-Situ Steam Generated (ISSG) SiO₂ Sept., 2000, Vol. 21, No. 9. **EXAMINER** DATE CONSIDERED haus Schule

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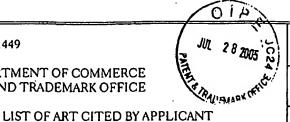
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APPLICANT Gurtej S. Sandhu

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Sheet 5 of 5 Form PTO-1449 ATTY. DOCKET NO. SERIAL NO. M122-1898 10/050,348 U.S. DEPARTMENT OF COMMERCE 347 **APPLICANT** PATENT AND TRADEMARK OFFICE Gurtej S. Sandhu LIST OF ART CITED BY APPLICAS THANK **GROUP** FILING DATE (Use several sheets if necessary) January 15, 2002 2813 U.S. PATENT DOCUMENTS Date Class Subclass Filing Date Document Name Examiner If Appropriate Initial Number AA 6,348,420 B1 02/02 Raaijmakers et al. 07/01 AB 6,265,327 Kobayashi et al. AC Liu et al. 6,350,707 B1 02/02 AD 6,723,599 B2 04/04 Eppich et al. ΑE 6,893,981 B2 05/05 Park et al. Beaman et al. AF 09/653,281 08/00 AG 2001/0036752 DeBoer et al. 11/01 08/98 Narwankar et al. AΗ 2002/0009861 Αl 05/02 Raaijmakers et al. 2002/0052124 2003/0034518A1 02/03 Yoshikawa FOREIGN PATENT DOCUMENTS Translation Date Country Class Subclass Document Number ΑK ΑL AM OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) AN AO AΡ **EXAMINER** DATE CONSIDERED

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